

FDP7042L / FDB7042L

N-Channel Logic Level PowerTrench® MOSFET

General Description

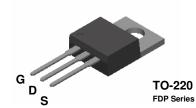
This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers. It has been optimized for "low side" synchronous rectifier operation, providing an extremely low $R_{\text{DS}(\text{ON})}$.

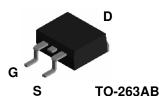
Applications

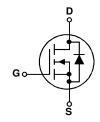
- · Synchronous rectifier
- DC/DC converter

Features

- 50 A, 30 V. $R_{DS(ON)} = 9 \ m\Omega \ @ \ V_{GS} = 4.5 \ V$ $R_{DS(ON)} = 7.5 \ m\Omega \ @ \ V_{GS} = 10 \ V$
- Critical DC electrical parameters specified at elevated temperature
- High performance trench technology for extremely low $R_{\text{DS}(\text{ON})}$
- 175°C maximum junction temperature rating







Absolute Maximum Ratings T_A=25°C unless otherwise noted

Symbol	Parameter	Ratings	Units
V _{DSS}	Drain-Source Voltage	30	V
V _{GSS}	Gate-Source Voltage	± 12	V
I _D	Drain Current - Continuous (Note 1)	50	Α
	- Pulsed (Note 1)	150	
P _D	Total Power Dissipation @ T _C = 25°C	83	W
	Derate above 25°C	0.48	W°C
T _J , T _{STG}	Operating and Storage Junction Temperature Range	-65 to +175	°C

FDB Series

Thermal Characteristics

$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	1.8	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	62.5	°C/W

Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape width	Quantity
FDB7042L	FDB7042L	13"	24mm	800 units
FDP7042L	FDP7042L	Tube	n/a	45

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Char	acteristics		I	l	l	ı
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = 250 \mu\text{A}$	30			V
ΔBV _{DSS} ΔT _J	Breakdown Voltage Temperature Coefficient	I_D = 250 μ A, Referenced to 25°C		24		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 24 \text{ V}, \qquad V_{GS} = 0 \text{ V}$			1	μΑ
I _{GSSF}	Gate-Body Leakage, Forward	$V_{GS} = 12 \text{ V}, \qquad V_{DS} = 0 \text{ V}$			100	nA
I _{GSSR}	Gate-Body Leakage, Reverse	$V_{GS} = -12 \text{ V}$ $V_{DS} = 0 \text{ V}$			-100	nA
On Char	acteristics (Note 2)					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$	0.8	1.2	2	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate Threshold Voltage Temperature Coefficient	I_D = 250 μ A, Referenced to 25°C		-4.1		mV/°C
R _{DS(on)}	Static Drain-Source On-Resistance	$\begin{tabular}{lllllllllllllllllllllllllllllllllll$		6.2 5.5 9.6	9 7.5 16	mΩ
I _{D(on)}	On-State Drain Current	$V_{GS} = 4.5 \text{ V}, \qquad V_{DS} = 10 \text{ V}$	60			Α
g _{FS}	Forward Transconductance	$V_{DS} = 5V$, $I_{D} = 25 A$		117		S
Dvnamic	Characteristics					
C _{iss}	Input Capacitance			2418		pF
C _{oss}	Output Capacitance	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V},$		549		pF
C _{rss}	Reverse Transfer Capacitance	f = 1.0 MHz		243		pF
Switchin	g Characteristics (Note 2)		I	ı		I
t _{d(on)}	Turn-On Delay Time			21	34	ns
t _r	Turn-On Rise Time	$V_{DD} = 15 \text{ V}, I_D = 1 \text{ A},$		20	32	ns
t _{d(off)}	Turn-Off Delay Time	$V_{\text{GS}} = 4.5 \text{ V}, \ \ R_{\text{GEN}} = 6 \ \Omega$		60	96	ns
t _f	Turn-Off Fall Time			30	48	ns
Qg	Total Gate Charge			32	51	nC
Q _{gs}	Gate-Source Charge	$V_{DS} = 15 \text{ V}, I_D = 50 \text{ A}, V_{GS} = 4.5 \text{ V}$		10		nC
Q _{gd}	Gate-Drain Charge	VGS - 7.0 V		9		nC
Drain-Se	ource Diode Characteristics a	and Maximum Ratings				
l _s	Maximum Continuous Drain–Source Diode Forward Current				50	Α
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = 25 \text{ A}$ (Note 2)		0.8	1.3	V

Notes:

- 1. Maximum continuous current is limited by the package.
- 2. Pulse Test: Pulse Width < 300μs, Duty Cycle < 2.0%

Typical Characteristics

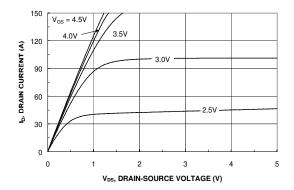


Figure 1. On-Region Characteristics.

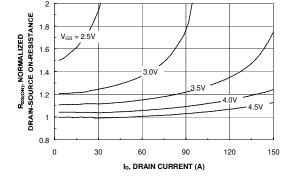


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

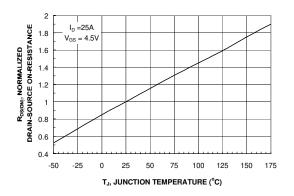


Figure 3. On-Resistance Variation withTemperature.

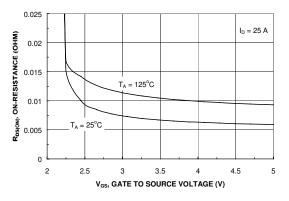


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

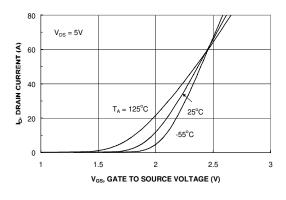


Figure 5. Transfer Characteristics.

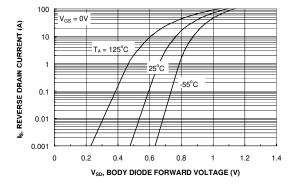
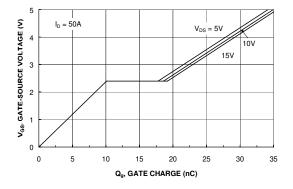


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics



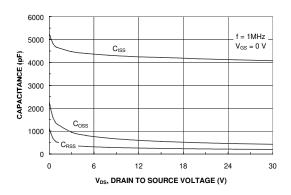
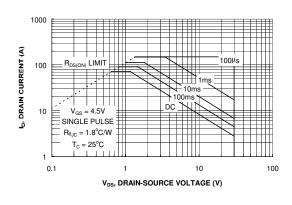


Figure 7. Gate Charge Characteristics.





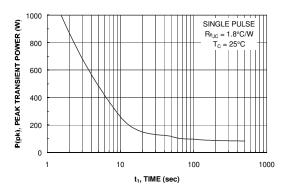


Figure 9. Maximum Safe Operating Area.

Figure 10. Single Pulse Maximum Power Dissipation.

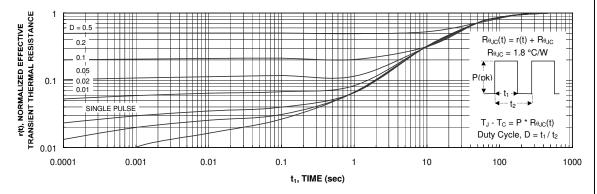


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1c. Transient thermal response will change depending on the circuit board design.

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